

Quench Analysis of Stacks of No-Insulation REBCO Coils Demonstrating Electromagnetic Quench Propagation and Self-Protecting Behavior

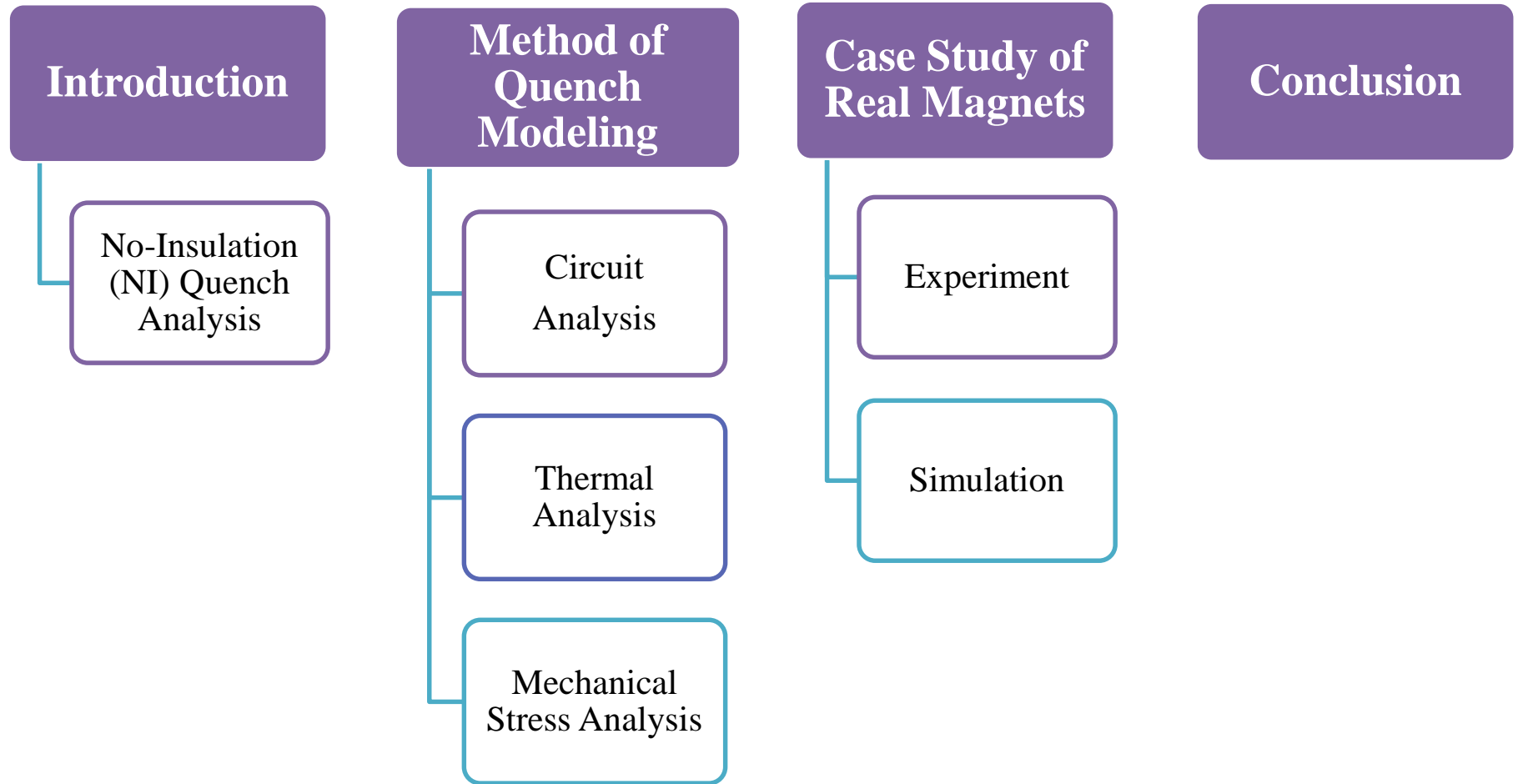
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Points of Discussion



□ No-Insulation Quench Analysis

NI Quench Modeling

Challenges:

- Anisotropic current path.
- Temperature rise and LHe consumption.
- Temperature dependent parameters.
- Unbalanced forces, stresses & strains.

Significance:

- Understanding of post quench situation ($I(t)$, $T(t)$, $\sigma(t)$, $\varepsilon(t)^*$) is important.
- Need to make sure T and ε are below certain limits.

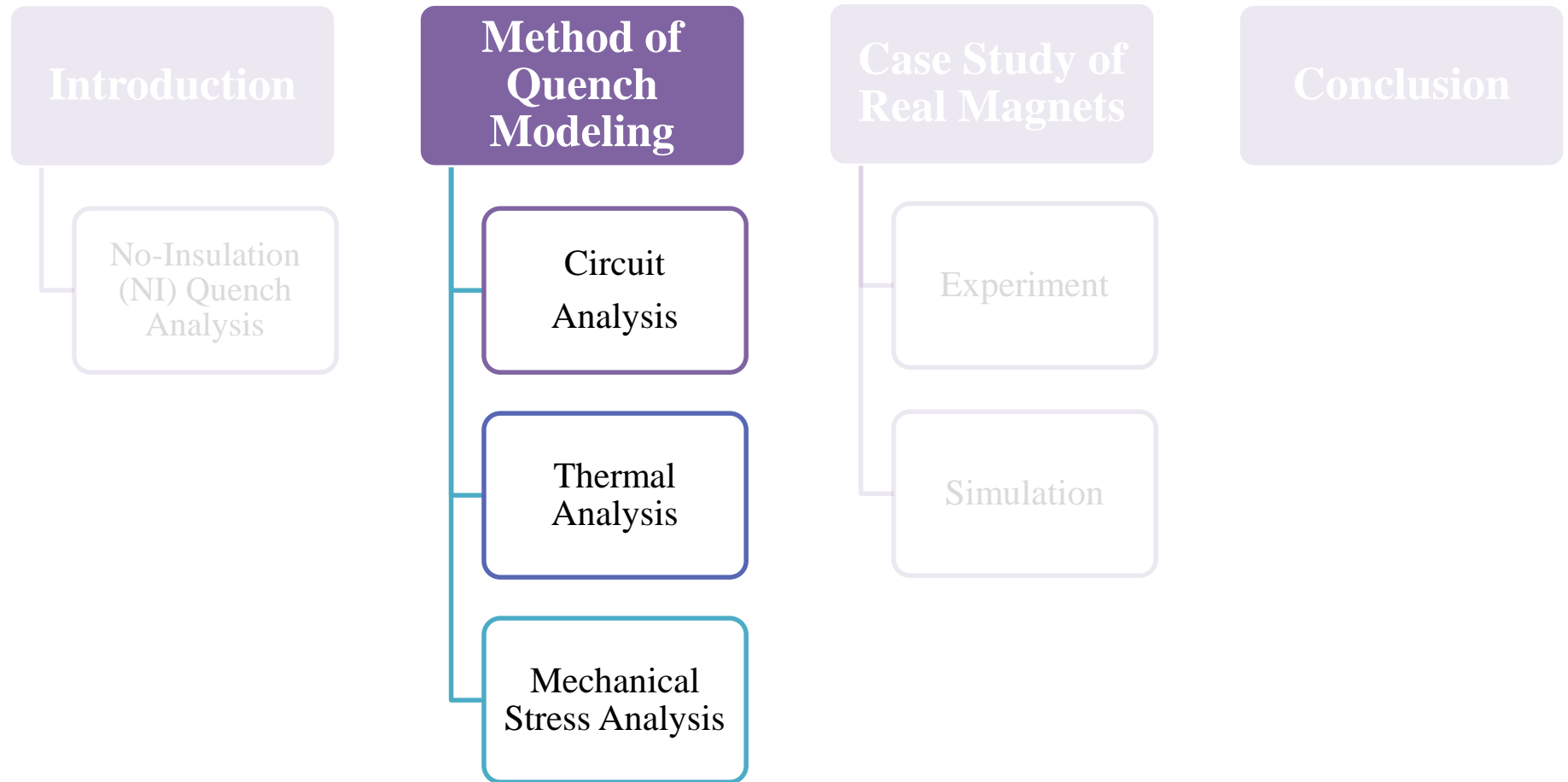
* $I(t)$: Operation current

$T(t)$: Temperature

$\sigma(t)$: Stress

$\varepsilon(t)$: Strain

Points of Discussion



Multi-Physics Quench Simulation

Circuit Analysis

To find $I(t)$ and $V(t)$ using Inductance / Resistance $[L/R]$ model.

Thermal Analysis

To find $T(t)$ rise due to resistive joule heating, I^2R .

Field Analysis

To find magnetic field, $B(t)$.

Stress Analysis

To find $\sigma_r(t)$, $\sigma_h(t)$ and $\sigma_z(t)$ due to Lorentz's forces.

Coupled, as resistivity (ρ), heat capacity (C_p) and critical current (I_c) are temperature dependent.

Coupled, as $B(t)$ is $I(t)$ dependent.

Coupled, as I_c is ϵ_h dependent.

□ Circuit Analysis

▪ Lumped Circuit Model:

Each coil is modeled as:

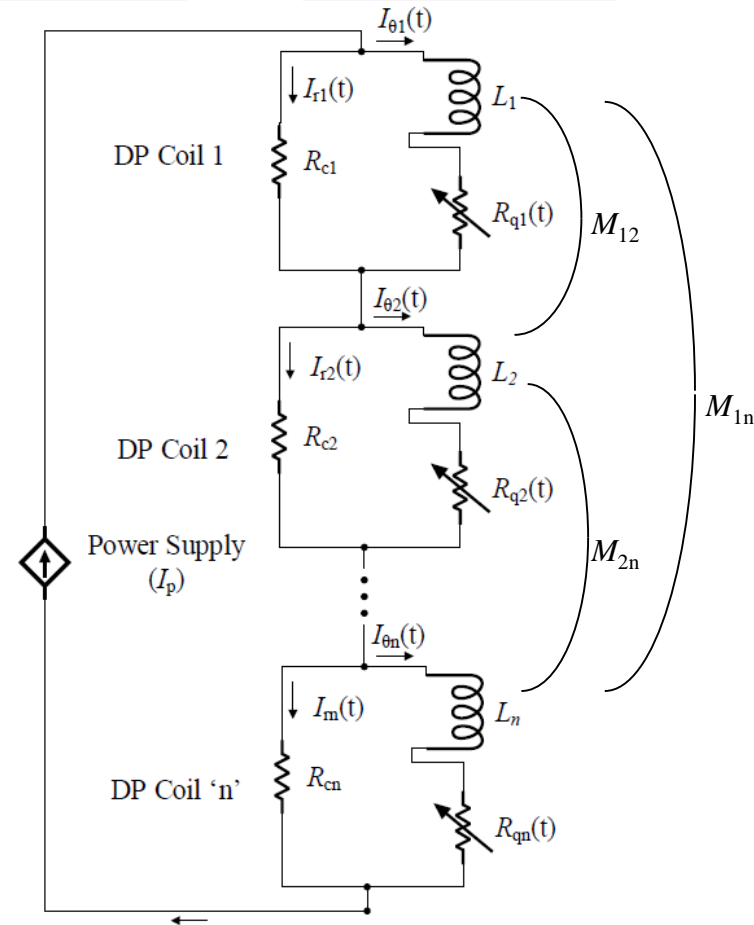
- Inductor, L - M ;
- Characteristic contact resistance, R_c ;
- Quench resistance, $R_q(t)$;

$$R_q(t) = \frac{V_c}{I(t)} \left(\frac{I_{\text{superconductor}}}{I_c(B(t), \theta(t))} \right)^n$$

▪ Field, Angle & Temperature Dependency of Critical Current, I_c

Modeled using expressions:

- David K. Hilton *et al.*, “Practical Fit Functions ...,” *Supercond. Sci. Technol.*, vol. 28, no. 7, June 2015.
- Carmine Senatore *et al.*, “Field and Temperature...,” *Supercond. Sci. Technol.*, vol. 29, no. 1, Dec 2015.



Equivalent L - R Circuit Model of No-Insulation Magnet with ‘n’ Number of Coils.

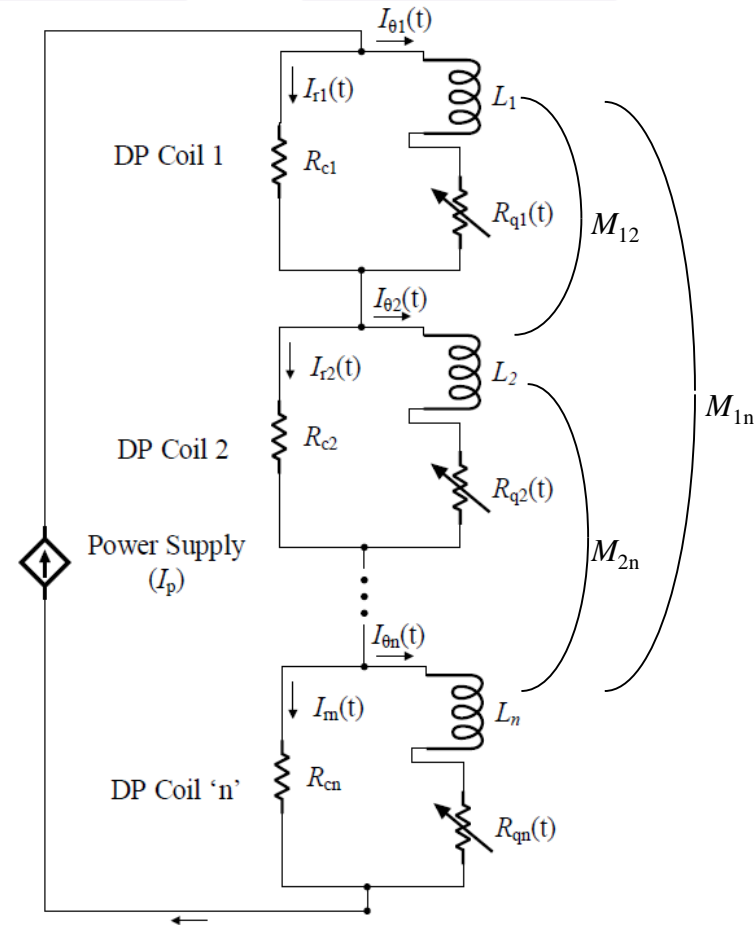
REF: K.R. Bhattarai *et al.*, “Quench Analysis of a Multiwidth...,” *IEEE Trans. Appl. Supercond.*, vol. 27, no. 4, p. 4603505, June 2017.

□ Circuit Analysis

- Governing ODEs from **Kirchhoff's Law** solved to obtain $I(t)$ and $V(t)$.

$$\begin{aligned}
 L_{11} \frac{dI_{op1}(t)}{dt} + M_{12} \frac{dI_{op2}(t)}{dt} + \dots + M_{1n} \frac{dI_{opn}(t)}{dt} + I_{op1}(t) R_{q1}(t) \\
 &= [I_p(t) - I_{op1}(t)] R_{c1} \\
 &\vdots \\
 M_{n1} \frac{dI_{op1}(t)}{dt} + M_{n2} \frac{dI_{op2}(t)}{dt} + \dots + L_{nn} \frac{dI_{opn}(t)}{dt} + I_{opn}(t) R_{qn}(t) \\
 &= [I_p(t) - I_{opn}(t)] R_{cn}
 \end{aligned}$$

- Advantage of Lumped Model:** Fast and seems reliable.
- Disadvantage of Lumped Model:** Not possible to obtain coil spatial information.



Equivalent L - R Circuit Model of No-Insulation Magnet with 'n' Number of Coils.

REF: K.R. Bhattarai *et al.*, "Quench Analysis of a Multiwidth...", *IEEE Trans. Appl. Supercond.*, vol. 27, no. 4, p. 4603505, June 2017.

□ Thermal Analysis

Joule Heating

$$\rho C_p \frac{dT}{dt} = \dot{q} + k \nabla^2 T + h(T - T_\infty) \frac{P}{A}$$

Heat Stored Heat Added Conduction Dissipation

$= 0$, (Lumped Capacitance Model Assumed)

$= 0$, (Adiabatic Assumption)

Simplified equation:

$$m C_p(t) \frac{dT(t)}{dt} = I(t)^2 R(t)$$

Thermal Analysis

- Solved to obtain $T(t)$
- $T(t)$ is used to recalculate parameters such as $R(t)$, $I_c(t)$ and $C_p(t)$.

Circuit Analysis

□ Mechanical Stress Analysis

- Radial stress [$\sigma_r(t)$] and hoop stress [$\sigma_\theta(t)$].

Force balance governing equation at magnet mid-plane:
$$r \frac{\partial \sigma_r}{\partial r} + \sigma_r - \sigma_\theta + r J_\theta B_z(r) = 0$$

REF: Bobrov, E.S. and Williams, J.E.C (1980) in *Mechanics of Superconducting Structures*, vol. 41, Proceedings of the Winter Annual Meeting Chicago, IL., November 16-21, 1980 (ed F.C. Moon), ASME, New York, pp.13-41.

- Stress in self supporting condition; $\sigma_\theta = B_z(r) \cdot J \cdot r$
- Solved to obtain $\sigma_r(t)$, $\sigma_\theta(t)$.
- Using generalized Hook's law, strain can be calculated.

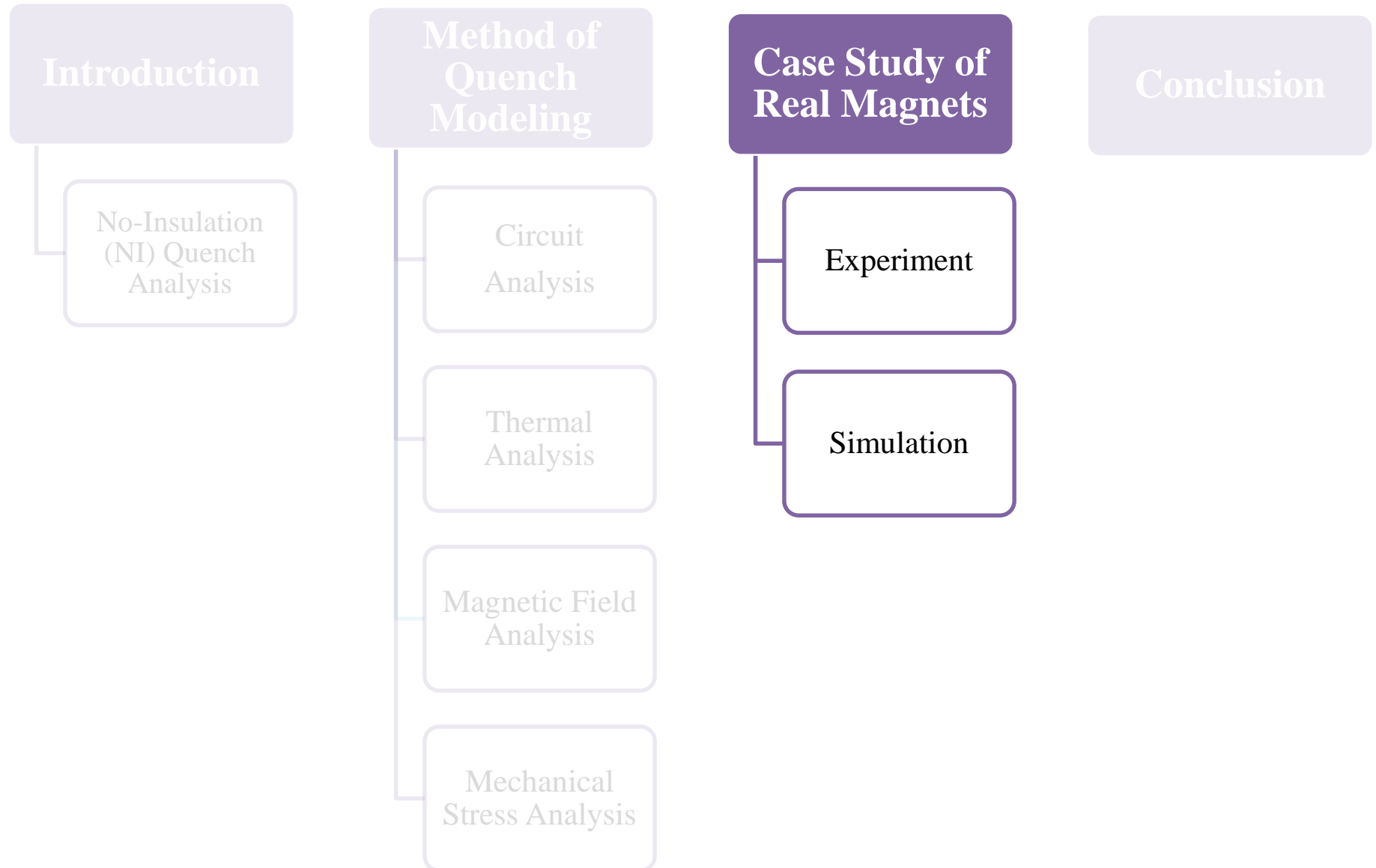
$$\varepsilon_r = \frac{\sigma_r}{E_r} - \nu_{hr} \frac{\sigma_h}{E_h} - \nu_{zr} \frac{\sigma_z}{E_z}$$

$$\varepsilon_h = \frac{\sigma_h}{E_h} - \nu_{rh} \frac{\sigma_r}{E_r} - \nu_{zh} \frac{\sigma_z}{E_z}$$

$$\varepsilon_z = \frac{\sigma_z}{E_z} - \nu_{rz} \frac{\sigma_r}{E_r} - \nu_{hz} \frac{\sigma_h}{E_h}$$

- 95% I_c retention when ε_h is $\sim 0.5\%$.

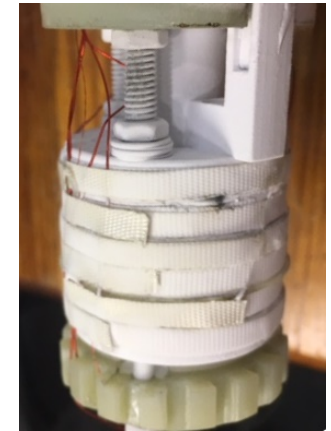
Points of Discussion



❑ Case Study I: 2 DP NI REBCO insert in 31.1 T background magnet.

- Some parameters that go into the simulation.

Parameters		Values
Tape width	[mm]	4.03
Tape thickness	[mm]	0.045; 0.01
Stabilizer material		Cu RRR50
Winding inner radius, a_1	[mm]	7
Winding outer radius, a_2	[mm]	17
Overall height	[mm]	16.48
Total number of turns		859
Inductance, L_{HTS}	[mH]	10.25
Measured characteristic resistance, R_c	[m Ω]	2.4
Young's modulus, E_r ; E_h ; E_z	[GPa]	69; 144; 144
Quench current	[A]	210



Case Study I: 2 DP NI REBCO insert in 31.1 T background magnet.

Experiment

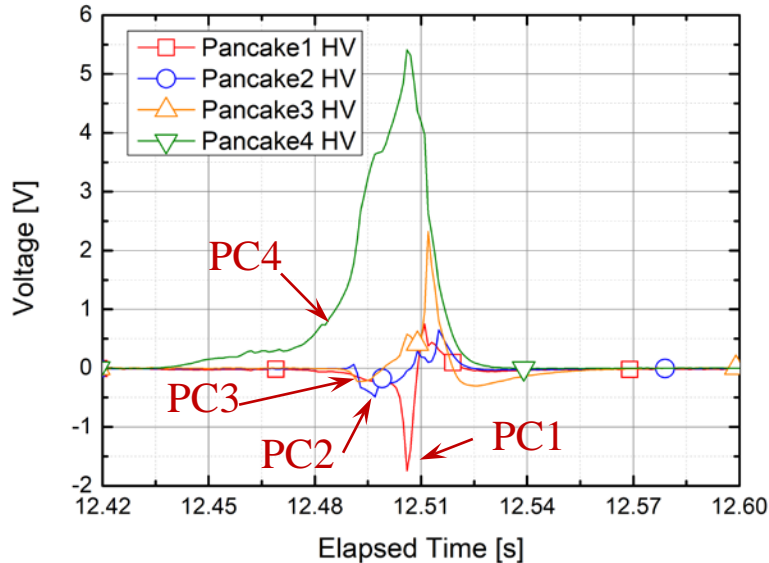
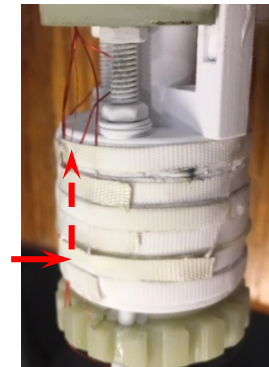
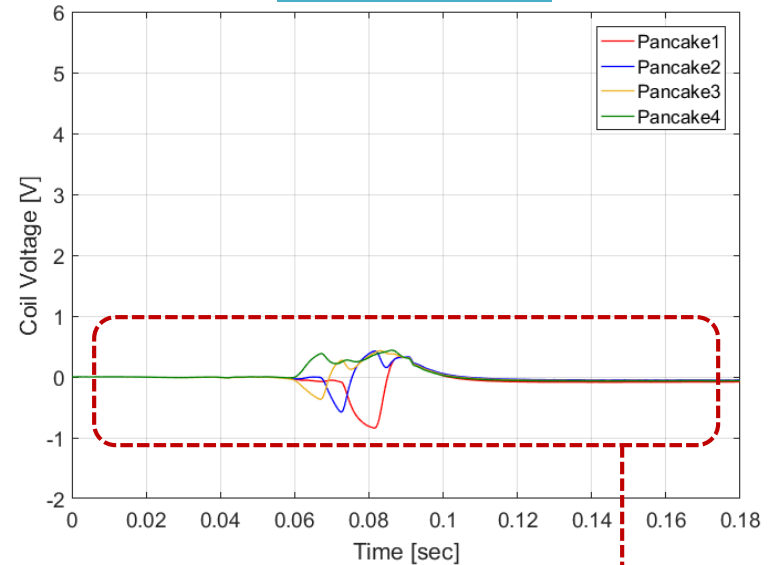


Table 1: Key Magnet Parameters

Parameters	Value
Inner radius [mm]	7
Outer Radius [mm]	17
Height [mm]	16.48
Time Constant [sec]	3.817
Quench Current [A]	210
Stored Energy [J]	240.8

Simulation

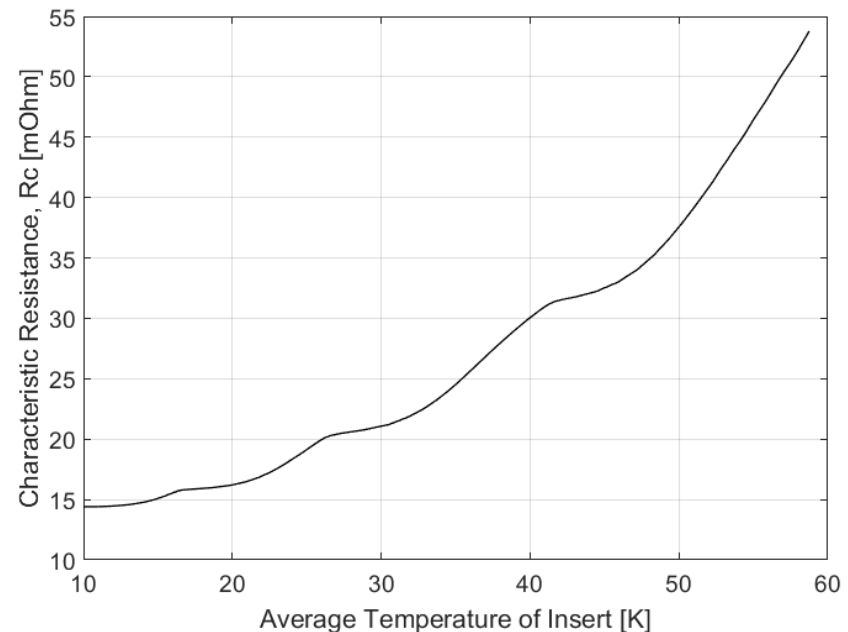
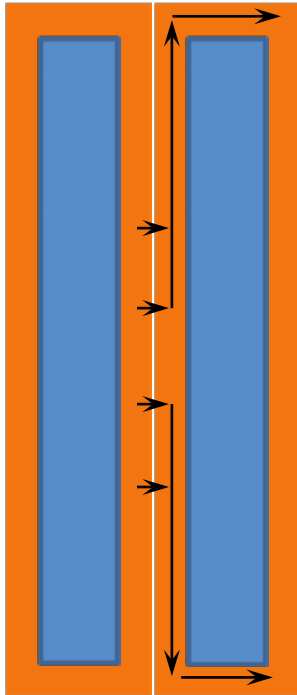


Significant error.
Simulation voltage range is only ~15% of the experimental voltage range.

□ Increase in Characteristic Resistance, R_c due to temperature rise.

- Assumption: R_c maybe increasing proportionally, as the copper resistivity rises with temperature.

$$R_c(T) = R_c(4.2) \frac{\rho_{cu}(T)}{\rho_{cu}(4.2)}$$



- R_c increase due to temperature rise is also proposed by J. Lu et al.

REF: J. Lu *et al.*, “Contact resistance between two REBCO tapes under load and load cycles,” *Supercond. Sci. Technol.*, vol. 30, p. 045005, 2017.

□ Case Study I: 2 DP T NI REBCO insert in 31.1 T background magnet.

- With variable Characteristic Resistance, R_c

Experiment

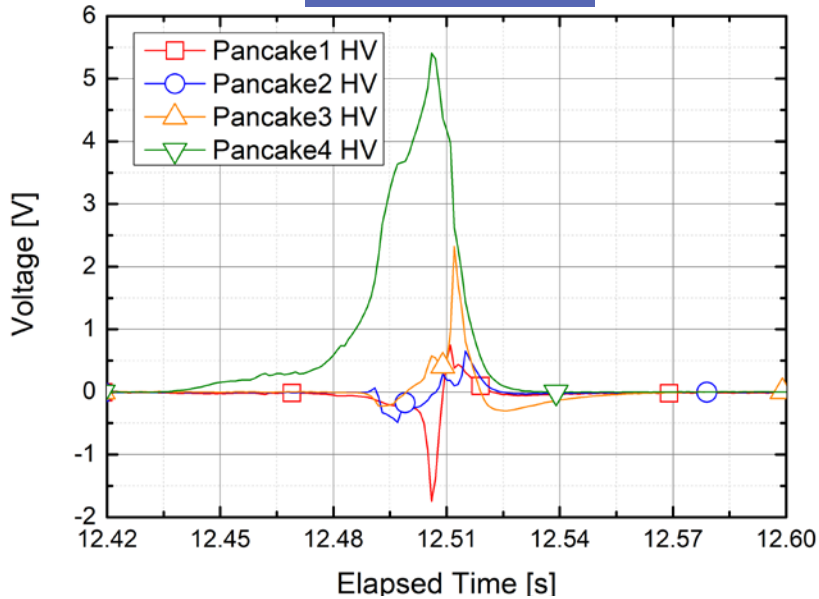
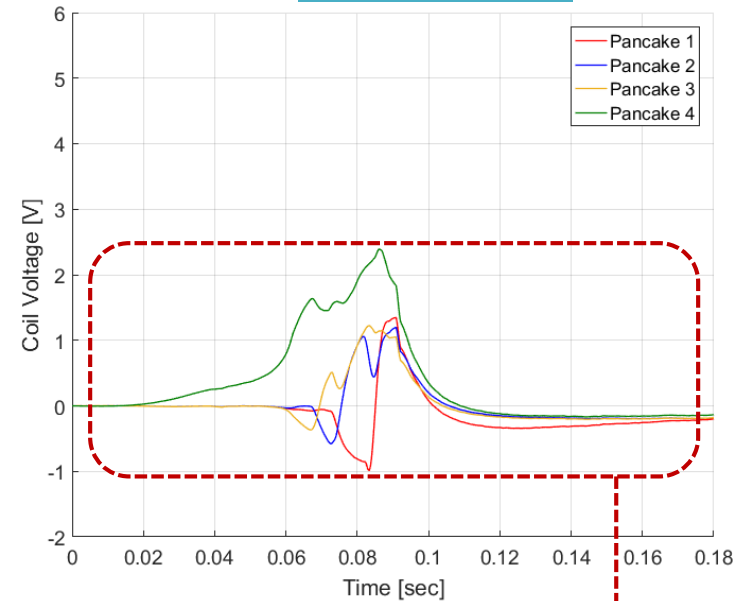


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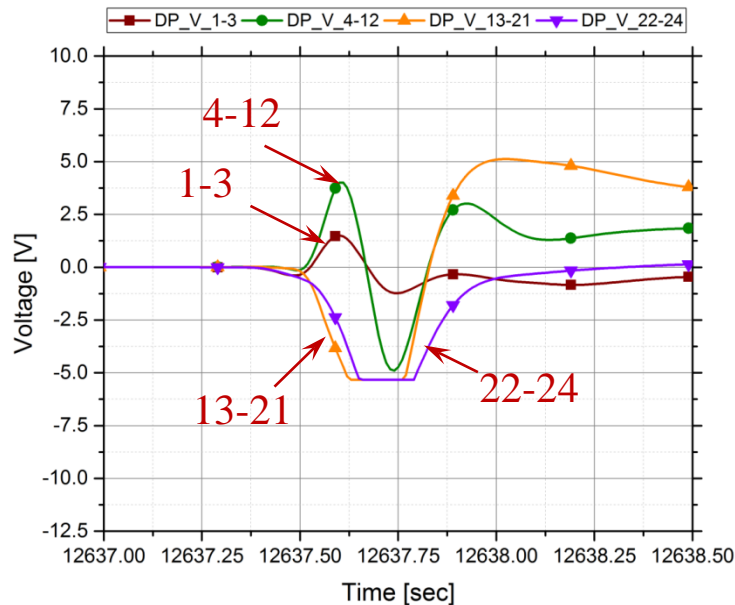


Simulation voltage range is about ~60% of the experimental voltage range

❑ Case Study II: 12.5 T NI REBCO insert in 6.5 T LTS.

- With variable Characteristic Resistance, R_c

Experiment



Simulation

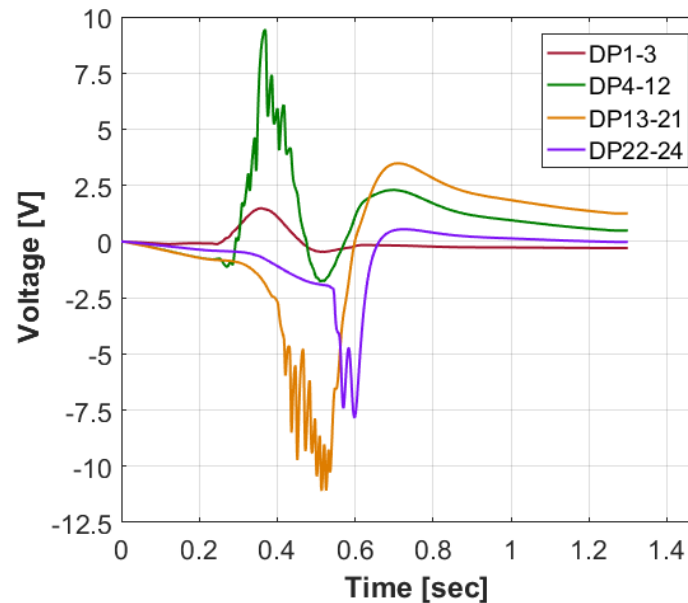
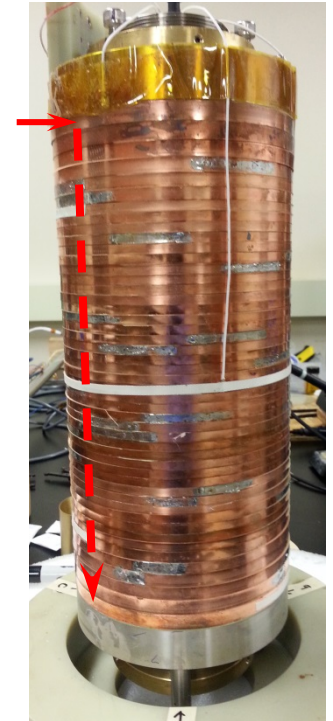


Table 1: Key Magnet Parameters

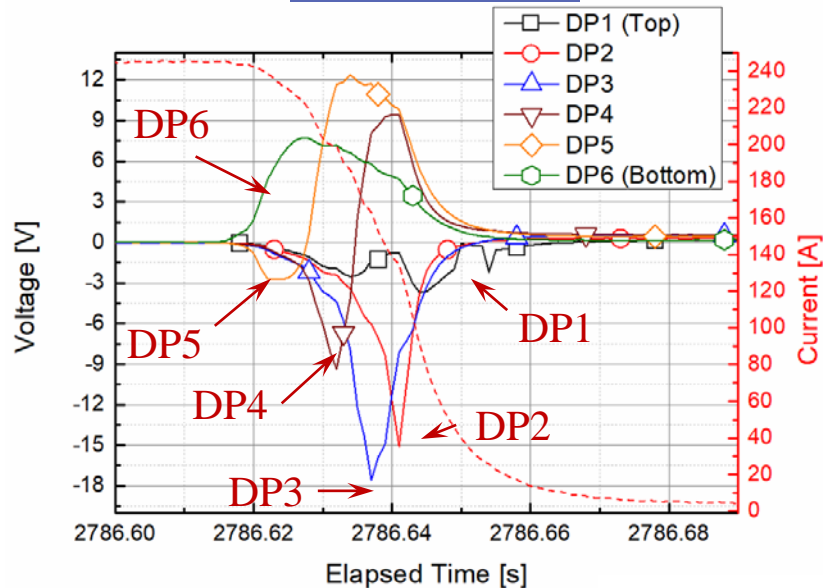
Parameters	Value
Inner radius [mm]	29.9
Outer Radius [mm]	57.5
Height [mm]	232.55
Time Constant [sec]	54
Quench Current [A]	216
Stored Energy [kJ]	62.99



REF: T. Painter *et al.*, “Design, Construction and Operation of a 13 T 52 mm No-Insulation REBCO Insert for a 20 T All-Superconducting User Magnet,” *Oral Presentation @ MT Conference 2017. Thu-Mo-Or31*

- Case Study III: 14.36 T NI REBCO insert in 31.1 T background magnet.
 - With variable Characteristic Resistance, R_c

Experiment



Simulation

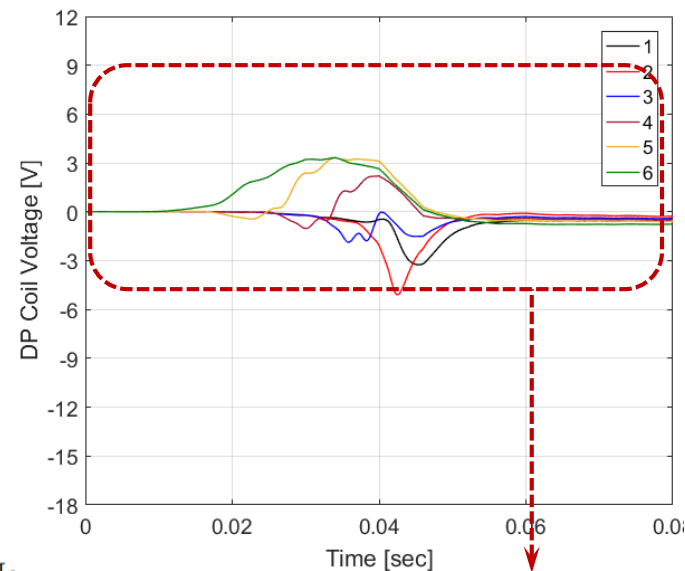


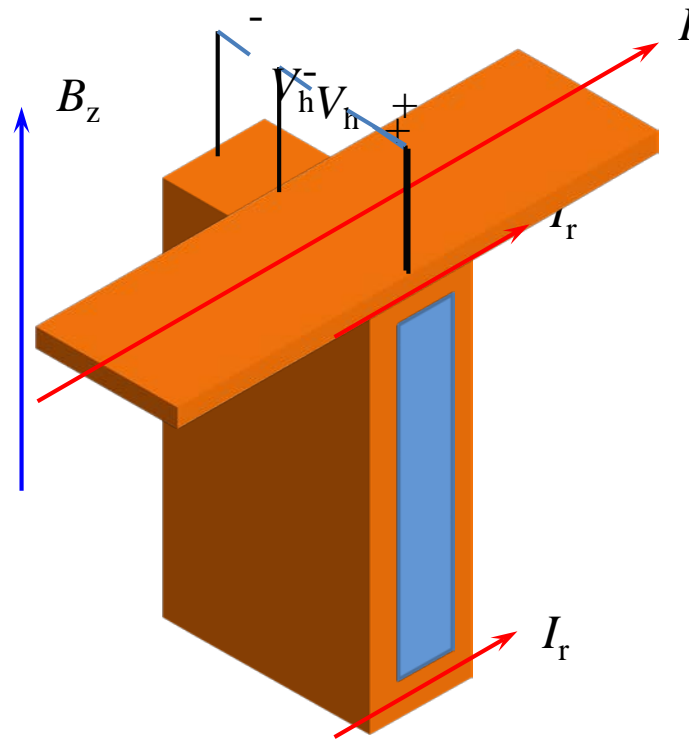
Table 1: Key Magnet Parameters

Parameters	Value
Inner radius [mm]	7
Outer Radius [mm]	17
Height [mm]	51
Time Constant [sec]	1.07
Quench Current [A]	245
Stored Energy [kJ]	1.512

Simulation voltage range is about ~30% of the experimental voltage range



□ Hall effect.



$$V_h = -R_h \mathbf{J} \times \mathbf{B}$$

I : Current [A]

I_r : Leak Current [A]

B_z : Axial Field [T]

V_h : Voltage due to Hall Effect [V]

R_h : Hall coefficient

- Proposed by So Noguchi et al.

REF: S. Noguchi *et al.*, “Electrical Field Generation by Hall Effect in High Field No-Insulation REBCO Pancake Coils,” *Poster Presentation @ MT Conference 2017*. [Thu-Af-Po4.11](#)

Case Study III: 14.36 T NI REBCO insert in 31.1 T background magnet.

- With variable Characteristic Resistance, R_c
- With Hall Effect

Experiment

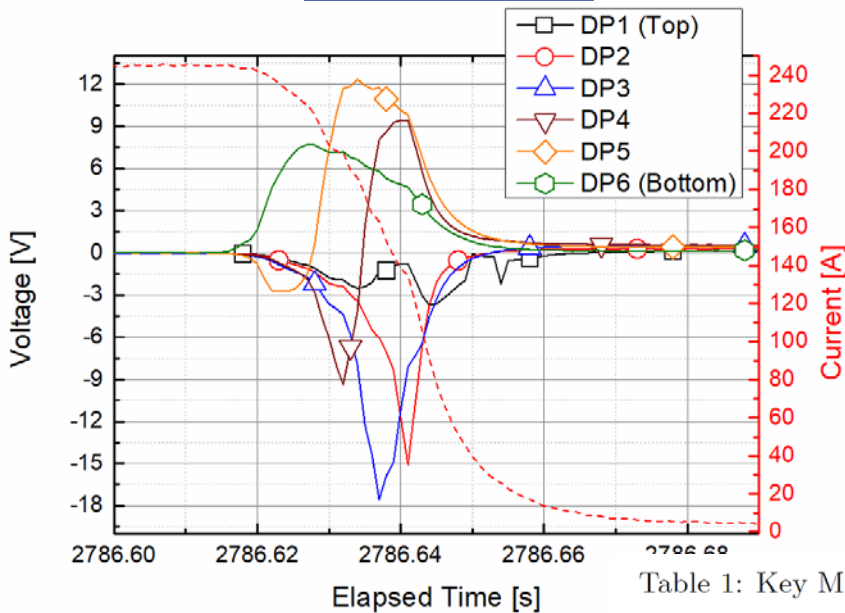
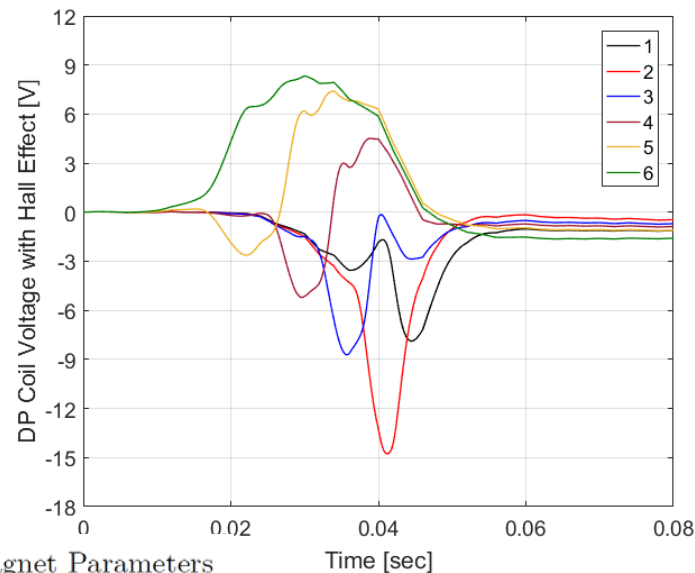


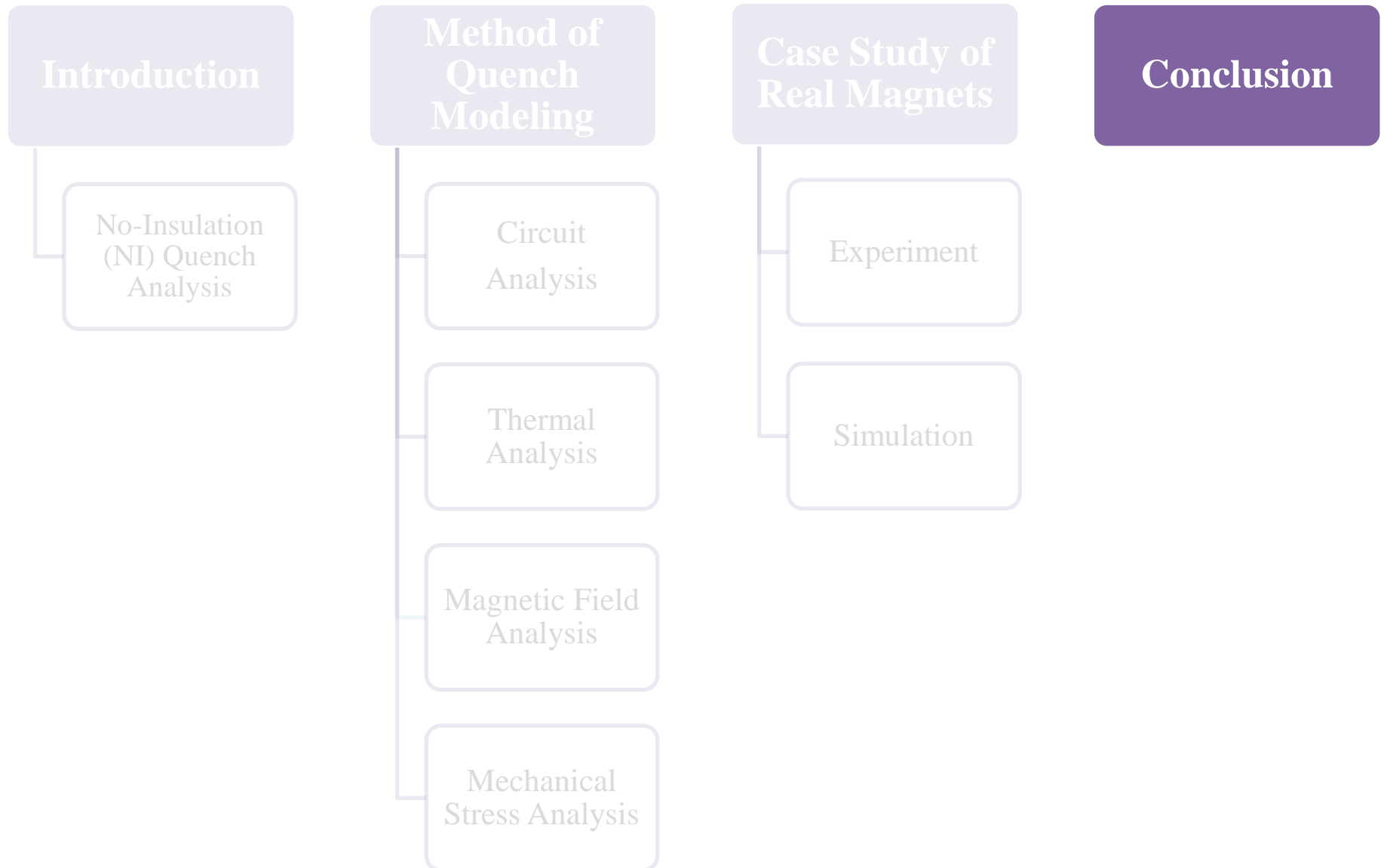
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Parameters	Value
Inner radius [mm]	7
Outer Radius [mm]	17
Height [mm]	51
Time Constant [sec]	1.07
Quench Current [A]	245
Stored Energy [kJ]	1.512

Simulation



Points of Discussion



❏ Discussion and Conclusion

- Characteristic Resistance, R_c seems to be increasing during quench. Possible reason is due to the increase in the resistivity of the contact material. This issue needs further research.
- Hall effect could be another contributor towards large voltage rise during quench. This effect also needs further research and validation.
- These are some of the first no-insulation simulations
 - i. of real magnets that have quenched.
 - ii. using lumped approach in magnet level.
- Lumped approach: computationally faster than distributed approaches.
- Despite limited accuracy, demonstrates electromagnetic interaction between coils during quench.

Thank you for your attention!